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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Huy A. Bui
Serial No. : 10/649,586
Filed : August 26, 2003
Title : OPTIMIZING SAMPLE PLATE PROCESSING IN A MALDI-TOF MASS SPECTROMETER

Art Unit : 2881
Examiner : Unknown

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 6/24/04

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Nikia M. Mc Nillion
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Substitute Form PTO-1449 (Modified) Information Disclosure Statement By Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12671-035001	Application No. 10/649,586
	Applicant Huy A. Bui		
	Filing Date August 26, 2003	Group Art Unit 2881	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	US 2002/0191864 A1	12/19/2002	Lennon et al.			
	AB	US 2003/0052859 A1	03/20/2003	Finley			
	AC	5,969,350	10/19/1999	Kerley et al.			
	AD	6,498,690 B2	12/24/2002	Ramm et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	Justin W. Torpey et al., "Validation Of Pattern Recognition Software With Automated Protein Identification Using An Orthogonal MALDI-QqTOF Mass Spectrometer", Applied BioSystems and MDS Sciex, 52 nd Annual ASMS Conference, June 2002
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	